74AHC3GU04

Inverter Rev. 04 — 7 January 2010

Product data sheet

General description 1.

The 74AHC3GU04 is a high-speed Si-gate CMOS device. This device provides three inverter gates with unbuffered outputs.

2. **Features**

- Symmetrical output impedance
- High noise immunity
- ESD protection:
 - ♦ HBM JESD22-A114F exceeds 2000 V
 - ♦ MM JESD22-A115-A exceeds 200 V
 - CDM JESD22-C101D exceeds 1000 V
- Low power dissipation
- Balanced propagation delays
- Multiple package options
- Specified from -40 °C to +85 °C and from -40 °C to +125 °C

Ordering information

Table 1. **Ordering information**

Type number	Package							
	Temperature range	Name	Description	Version				
74AHC3GU04DP	–40 °C to +125 °C	TSSOP8	plastic thin shrink small outline package; 8 leads; body width 3 mm; lead length 0.5 mm	SOT505-2				
74AHC3GU04DC	–40 °C to +125 °C	VSSOP8	plastic very thin shrink small outline package; 8 leads; body width 2.3 mm	SOT765-1				
74AHC3GU04GD	–40 °C to +125 °C	XSON8U	plastic extremely thin small outline package; no leads; 8 terminals; UTLP based; body 3 \times 2 \times 0.5 mm	SOT996-2				

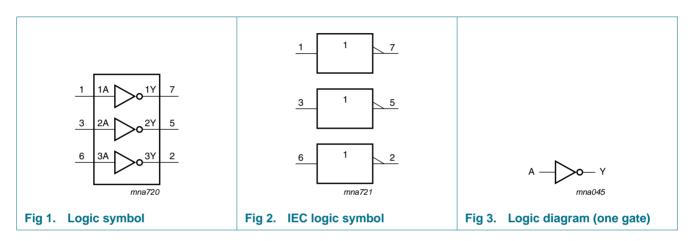


4. Marking

Table 2. Marking codes

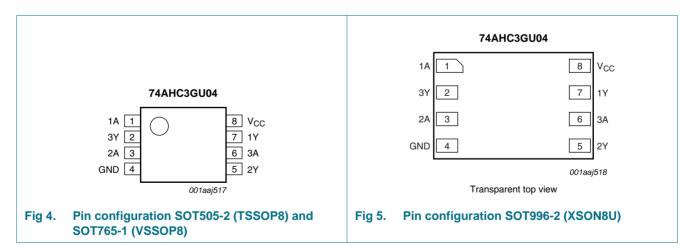
Type number	Marking code
74AHC3GU04DP	AU4
74AHC3GU04DC	AU4
74AHC3GU04GD	AU4

5. Functional diagram



6. Pinning information

6.1 Pinning



6.2 Pin description

Table 3. Pin description

Symbol	Pin	Description
1A, 2A, 3A	1, 3, 6	data input
GND	4	ground (0 V)
1Y, 2Y, 3Y	7, 5, 2	data output
V_{CC}	8	supply voltage

7. Functional description

Table 4. Function table

H = HIGH voltage level; L = LOW voltage level

Input	Output
Α	Υ
L	Н
Н	L

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		-0.5	+7.0	V
VI	input voltage		-0.5	+7.0	V
I_{IK}	input clamping current	$V_1 < -0.5 \text{ V}$	<u>[1]</u> –20	-	mA
I _{OK}	output clamping current	$V_O < -0.5 \text{ V or } V_O > V_{CC} + 0.5 \text{ V}$	<u>[1]</u> -	±20	mA
I _O	output current	$-0.5 \text{ V} < \text{V}_{\text{O}} < \text{V}_{\text{CC}} + 0.5 \text{ V}$	-	±25	mA
I _{CC}	supply current		-	75	mA
I_{GND}	ground current		-75	-	mA
T _{stg}	storage temperature		-65	+150	°C
P _{tot}	total power dissipation	$T_{amb} = -40 ^{\circ}\text{C}$ to +125 $^{\circ}\text{C}$	[2] -	250	mW

^[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

^[2] For TSSOP8 package: above 55 °C the value of P_{tot} derates linearly with 2.5 mW/K. For VSSOP8 package: above 110 °C the value of P_{tot} derates linearly with 8 mW/K. For XSON8U package: above 45 °C the value of P_{tot} derates linearly with 2.4 mW/K.

9. Recommended operating conditions

Table 6. Recommended operating conditions

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{CC}	supply voltage		2.0	5.0	5.5	V
VI	input voltage		0	-	5.5	V
Vo	output voltage		0	-	V_{CC}	V
T _{amb}	ambient temperature		-40	+25	+125	°C
Δt/ΔV	input transition rise and fall rate	V_{CC} = 3.3 V \pm 0.3 V	-	-	100	ns/V
		$V_{CC} = 5.0 \text{ V} \pm 0.5 \text{ V}$	-	-	20	ns/V

10. Static characteristics

Table 7. Static characteristics

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		25 °C		-40 °C to +85 °C		-40 °C to +125 °C		Unit
			Min	Тур	Max	Min	Max	Min	Max	
V_{IH}	HIGH-level	V _{CC} = 2.0 V	1.7	-	-	1.7	-	1.7	-	V
	input voltage	V _{CC} = 3.0 V	2.4	-	-	2.4	-	2.4	-	V
		V _{CC} = 5.5 V	4.4	-	-	4.4	-	4.4	-	V
V _{IL}	LOW-level	V _{CC} = 2.0 V	-	-	0.3	-	0.3	-	0.3	V
	input voltage	V _{CC} = 3.0 V	-	-	0.6	-	0.6	-	0.6	V
		V _{CC} = 5.5 V	-	-	1.1	-	1.1	-	1.1	V
V _{OH}	HIGH-level	$V_I = V_{IH}$ or V_{IL}								
	output voltage	$I_O = -50 \mu A$; $V_{CC} = 2.0 \text{ V}$	1.9	2.0	-	1.9	-	1.9	-	V
		$I_O = -50 \mu A$; $V_{CC} = 3.0 \text{ V}$	2.9	3.0	-	2.9	-	2.9	-	V
		$I_{O} = -50 \mu A$; $V_{CC} = 4.5 V$	4.4	4.5	-	4.4	-	4.4	-	V
		$I_{O} = -4.0 \text{ mA}; V_{CC} = 3.0 \text{ V}$	2.58	-	-	2.48	-	2.40	-	V
		$I_{O} = -8.0 \text{ mA}; V_{CC} = 4.5 \text{ V}$	3.94	-	-	3.8	-	3.70	-	V
V_{OL}	LOW-level	$V_I = V_{IH}$ or V_{IL}								
	output voltage	$I_O = 50 \mu A; V_{CC} = 2.0 V$	-	0	0.1	-	0.1	-	0.1	V
		$I_O = 50 \mu A; V_{CC} = 3.0 V$	-	0	0.1	-	0.1	-	0.1	V
		$I_O = 50 \mu A; V_{CC} = 4.5 V$	-	0	0.1	-	0.1	-	0.1	V
		$I_O = 4.0 \text{ mA}; V_{CC} = 3.0 \text{ V}$	-	-	0.36	-	0.44	-	0.55	V
		$I_{O} = 8.0 \text{ mA}; V_{CC} = 4.5 \text{ V}$	-	-	0.36	-	0.44	-	0.55	V
II	input leakage current	$V_I = 5.5 \text{ V or GND};$ $V_{CC} = 0 \text{ V to } 5.5 \text{ V}$	-	-	0.1	-	1.0	-	2.0	μА
Icc	supply current	$V_I = V_{CC}$ or GND; $I_O = 0$ A; $V_{CC} = 5.5 \text{ V}$	-	-	1.0	-	10	-	40	μΑ
C _I	input capacitance		-	3.0	10	-	10	-	10	pF

11. Dynamic characteristics

Table 8. Dynamic characteristics GND = 0 V; For test circuit see Figure 7.

Symbol	Parameter	Conditions		25 °C		-40 °C to +85 °C		-40 °C to +125 °C		Unit	
					Тур	Max	Min	Max	Min	Max	
t _{pd} propa delay	propagation	nA to nY; see Figure 6	[1]	•	•	'				'	
	delay	$V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$	[2]								
		$C_{L} = 15 \text{ pF}$		-	3.0	7.1	1.0	8.5	1.0	10.0	ns
		$C_L = 50 pF$		-	4.3	10.6	1.0	12.0	1.0	13.5	ns
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	[3]								
		$C_{L} = 15 pF$		-	2.5	5.5	1.0	6.0	1.0	7.0	ns
		$C_L = 50 pF$		-	3.5	7.0	1.0	8.0	1.0	9.0	ns
C_{PD}	power dissipation capacitance	per buffer; $V_I = GND$ to V_{CC}	<u>[4]</u>	-	4	-	-	-	-	-	pF

- [1] t_{pd} is the same as t_{PLH} and t_{PHL} .
- [2] Typical values are measured at $V_{CC} = 3.3 \text{ V}$.
- [3] Typical values are measured at $V_{CC} = 5.0 \text{ V}$.
- [4] C_{PD} is used to determine the dynamic power dissipation (P_D in μW).

 $P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma (C_L \times V_{CC}^2 \times f_o)$ where:

f_i = input frequency in MHz;

fo = output frequency in MHz;

C_L = output load capacitance in pF;

V_{CC} = supply voltage in V;

N = number of inputs switching;

 $\Sigma(C_L \times V_{CC}^2 \times f_o)$ = sum of the outputs.

12. Waveforms

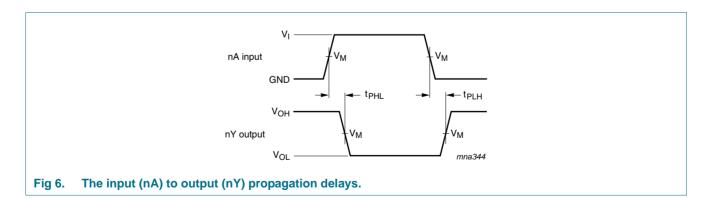
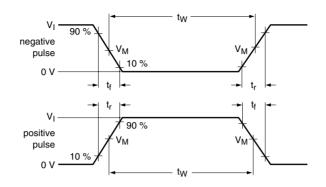
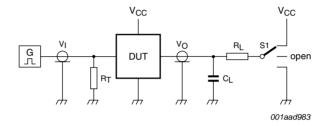


Table 9. Measurement points

Туре	Input	Output
	V_{M}	V_{M}
74AHC3GU04	0.5V _{CC}	0.5V _{CC}





Test data is given in Table 10.

Definitions test circuit:

 R_T = Termination resistance should be equal to output impedance Z_o of the pulse generator.

 C_L = Load capacitance including jig and probe capacitance.

R_L = Load resistance.

S1 = Test selection switch.

Test circuit for measuring switching times Fig 7.

Table 10. Test data

Туре	Input		Load	Load		S1 position		
	VI	t _r , t _f	CL	R _L	t _{PHL} , t _{PLH}	t _{PZH} , t _{PHZ}	t _{PZL} , t _{PLZ}	
74AHC3GU04	V_{CC}	≤ 3 ns	15 pF, 50 pF	1 kΩ	open	GND	V_{CC}	

13. Typical transfer characteristics

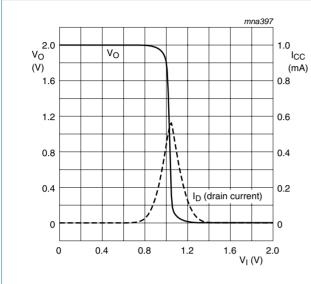


Fig 8. $V_{CC} = 2.0 \text{ V}; I_O = 0 \text{ A}$

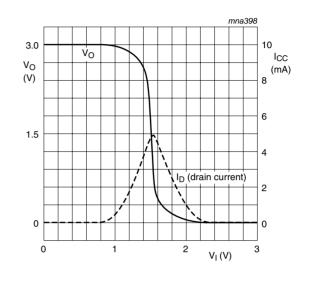


Fig 9. $V_{CC} = 3.0 \text{ V}$; $I_{O} = 0 \text{ A}$

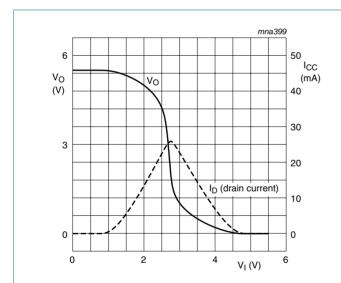


Fig 10. $V_{CC} = 5.5 \text{ V}$; $I_O = 0 \text{ A}$

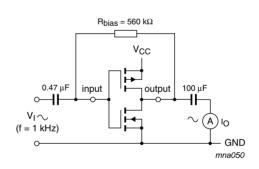


Fig 11. Test set-up for measuring forward transconductance $g_{fs}=\Delta I_O/\Delta V_I$ at V_O is constant

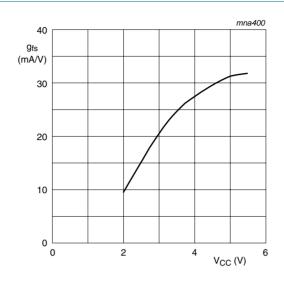


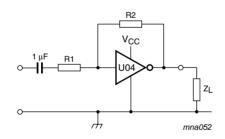
Fig 12. Typical forward transconductance g_{fs} as a function of the supply voltage at T_{amb} = 25 °C

14. Application information

Some applications are:

- Linear amplifier (see Figure 13)
- In crystal oscillator design (see Figure 14)

Remark: All values given are typical unless otherwise specified.



Maximum $V_{o(p-p)} = V_{CC} - 1.5 \text{ V}$ centered at $0.5 \times V_{CC}$.

$$G_{v} = -\frac{G_{ol}}{I + \frac{RI}{R2}(I + G_{ol})}$$

Gol = open loop gain

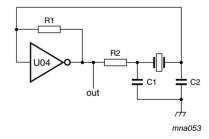
G_v = voltage gain

 $R1 \ge 3 \text{ k}\Omega, R2 \le 1 \text{ M}\Omega$

 $Z_L > 10 \text{ k}\Omega$; $G_{ol} = 20 \text{ (typ.)}$

Typical unity gain bandwidth product is 5 MHz.

Fig 13. Used as a linear amplifier



C1 = 47 pF (typ.)

C2 = 22 pF (typ.)

R1 = 1 M Ω to 10 M Ω (typ.)

R2 optimum value depends on the frequency and required stability against changes in V_{CC} or average minimum I_{CC} (I_{CC} is typically 2 mA at V_{CC} = 3 V and f = 1 MHz).

Fig 14. Crystal oscillator configuration

9 of 15

Table 11. External components for resonator (f < 1 MHz)

All values given are typical and must be used as an initial set-up.

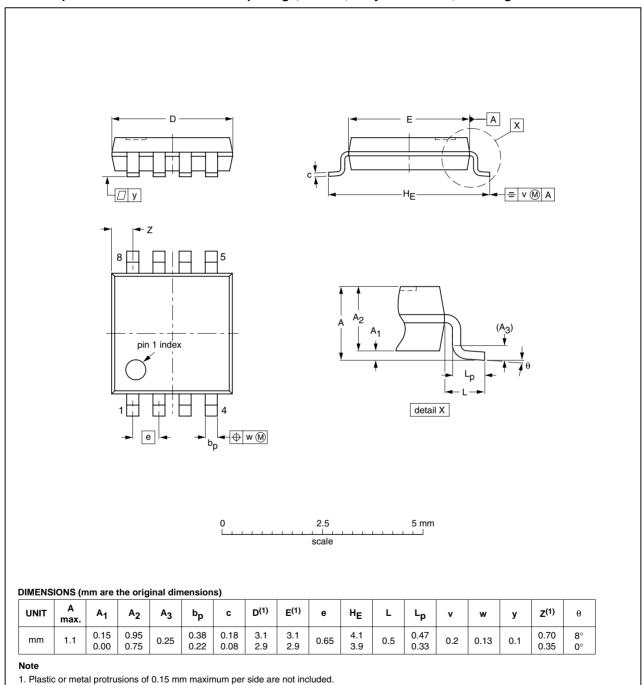
Frequency	R1	R2	C1	C2
10 kHz to 15.9 kHz	22 M Ω	220 kΩ	56 pF	20 pF
16 kHz to 24.9 kHz	22 MΩ	220 kΩ	56 pF	10 pF
25 kHz to 54.9 kHz	22 MΩ	100 kΩ	56 pF	10 pF
55 kHz to 129.9 kHz	22 MΩ	100 kΩ	47 pF	5 pF
130 kHz to 199.9 kHz	22 MΩ	47 kΩ	47 pF	5 pF
200 kHz to 349.9 kHz	22 MΩ	47 kΩ	47 pF	5 pF
350 kHz to 600 kHz	22 M $Ω$	47 kΩ	47 pF	5 pF

Table 12. Optimum value for R2

Frequency	R2	Optimum for
3 kHz 2.0 kΩ		minimum required I _{CC}
	8.0 kΩ	minimum influence due to change in V _{CC}
6 kHz	1.0 kΩ	minimum required I _{CC}
	4.7 kΩ	minimum influence by V _{CC}
10 kHz	0.5 kΩ	minimum required I _{CC}
	2.0 kΩ	minimum influence by V _{CC}
14 kHz	0.5 kΩ	minimum required I _{CC}
	1.0 kΩ	minimum influence by V _{CC}
>14 kHz	-	replace R2 by C3 with a typical value of 35 pF

15. Package outline

TSSOP8: plastic thin shrink small outline package; 8 leads; body width 3 mm; lead length 0.5 mm SOT505-2



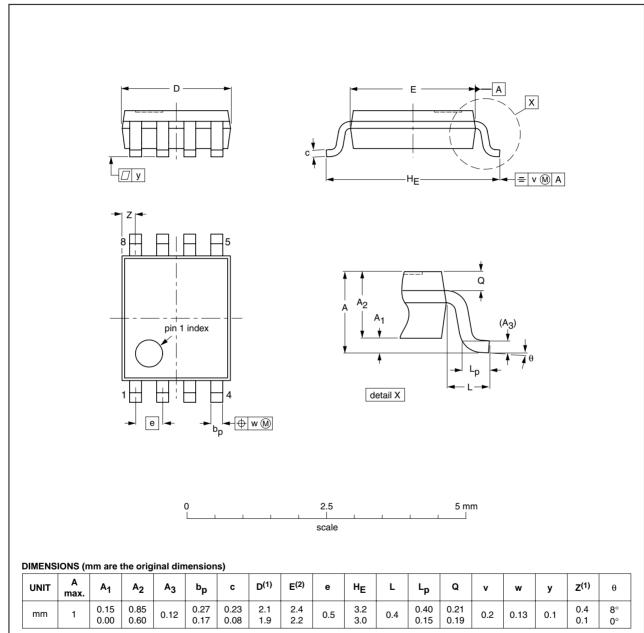
OUTLINE	REFERENCES				EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT505-2						02-01-16

Fig 15. Package outline SOT505-2 (TSSOP8)

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VSSOP8: plastic very thin shrink small outline package; 8 leads; body width 2.3 mm

SOT765-1



Notes

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

VERSION IEC JEDEC JEITA PROJECTION	OUTLINE	REFERENCES			EUROPEAN	ISSUE DATE	
SOT765-1 MO-187 02-06-07	VERSION	IEC	JEDEC	JEITA		PROJECTION	1330E DATE
	SOT765-1		MO-187				02-06-07

Fig 16. Package outline SOT765-1 (VSSOP8)

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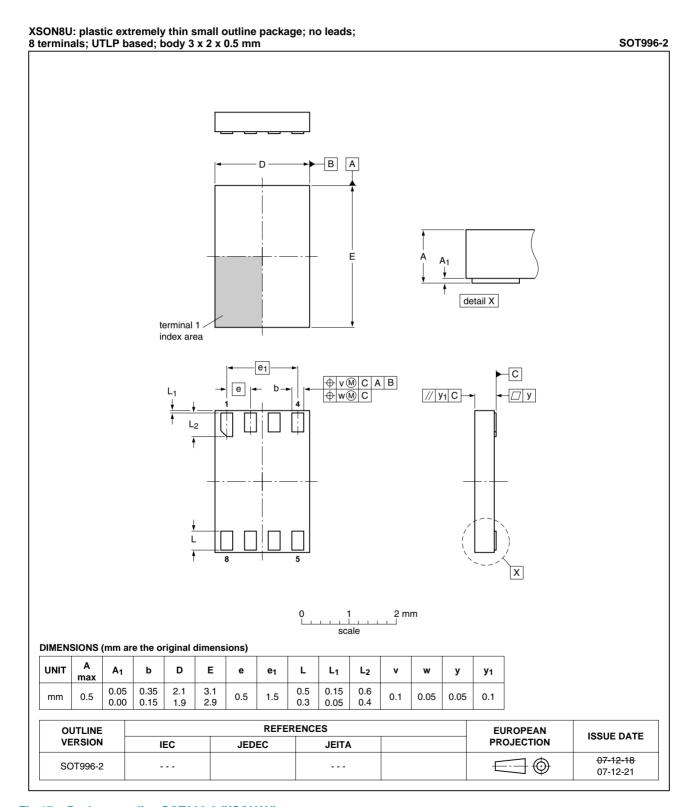


Fig 17. Package outline SOT996-2 (XSON8U)

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16. Abbreviations

Table 13. Abbreviations

Acronym	Description	
CDM	Charged Device Model	
CMOS	Complementary Metal-Oxide Semiconductor	
DUT	Device Under Test	
ESD	ElectroStatic Discharge	
НВМ	Human Body Model	
MM	Machine Model	

17. Revision history

Table 14. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74AHC3GU04_4	20100107	Product data sheet	-	74AHC3GU04_3
	 Marking code 	e for 74AHC3GU04DP packag	e changed from AU	04 to AU4
74AHC3GU04_3	20090126	Product data sheet	-	74AHC3GU04_2
74AHC3GU04_2	20040923	Product specification	-	74AHC3GU04_1
74AHC3GU04_1	20040305	Product specification	-	-

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18.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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